

#### Genera Description 概述

Specifically designed for Automotive applications, this SiC Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per unit area.

本产品是一款专为汽车应用设计的碳化硅功率MOSFET产品,采用了最先进的工艺技术,产品的单位面积导通电阻非常低。

#### **Features**

#### 特点

- High Speed Switching with Low Capacitances
   开关速度快,寄生电容小
- High Blocking Voltage with Low R<sub>DS(on)</sub>
   阻断电压高,开通电阻低
- 100% avalanche tested100%通过雪崩测试
- Halogen Free and RoHS Compliant 无卤元素,符合 RoHS



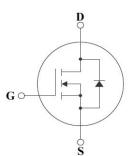
- EV ChargingEV 充电
- DC-AC Inverters
   DC-AC 转换器
- High Voltage DC/DC Converters
   高压 DC/DC 变压器
- Power Factor Correction Modules
   功率因子矫正模块

# **Ordering Information**

订货信息

Type	BV <sub>DSS</sub> [V]	R <sub>DSon</sub> [mΩ]	T <sub>jmax</sub> [℃]	Marking	Packing
型号	漏极-源极电压	导通电阻	最高结温	标记	封装外形
BSN160S120	1200	160	175	BSN160S120	TO247







# **Maximum Rated Values**

# 最大额定参数

Parameter 参数	Symbol 符号	Value 数值	Unit 单位
Drain-Source Voltage, Tj≥25℃ 漏-源电压, Tj≥25℃	V <sub>DSS</sub>	1200	V
Drain Current(continuous)at T <sub>C</sub> =25℃ 常温下漏极电流(持续)	Ţ	17	
Drain Current(continuous)at T <sub>C</sub> =100℃ T <sub>C</sub> =100℃下漏极电流(持续)	$ I_{\mathrm{D}}$	11	A
Pulsed Drain current, tp limited by Tj max 集电极脉冲电流,脉宽时间受 Tj max 限制	$I_{D,pulse}$	38	
Gate-Source Voltage 栅极-源极电压	$ m V_{GSS}$	-10/+25	V
Gate-Source Voltage (Recommended operational values) 栅极-源极电压(推荐工作电压)	$V_{ m GSS}$	-5/+20	V
Power Dissipation T <sub>C</sub> = 25°C <sup>(Fig.10)</sup> 常温耗散功率	P <sub>D</sub>	153	W
Storage Temperature Range 储存温度范围	T <sub>J.Tstg</sub>	-55 to +175	
Solder Temperature 焊接温度	$T_{L}$	260	°C
Operating junction temperature Range 工作结温	TJ	-55 to +175	

Caution: These values must not be exceeded under any conditions.

注意: 任何条件下都不能超出上述值。

#### **Thermal Resistance**

## 热阻

Parameter 参数	Symbol 符号	Value 值	Unit 单位
Thermal Resistance, Junction to Case, Max. 结-管壳热阻(Fig.11)	$R_{ heta JC}$	0.98	°C/W
Thermal Resistance, Junction to Ambient, Max. 结-环境热阻	$R_{ heta JA}$	40	-C/W



# Electrical Characteristic at $Tj = 25^{\circ}C$ (unless otherwise specified)

Tj=25℃时电学特性(除非特别声明)

Parameter	Symbol	Conditions	Value 值			Unit
多数	符号	条件	Min. 最小 值	Typ. 典型 值	Max. 最大 值	单位
Static Characteristic 静态特性						
Drain to Source Breakdown Voltage 漏极-源极电压击穿电压	BV <sub>DSS</sub>	$V_{GS}$ =0V, $I_{D}$ =100 $\mu$ A $T_{j}$ =25°C	1200	-	-	V
Zero Gate Voltage Drain Current 栅源短路的漏极电流	$I_{DSS}$	V <sub>DS</sub> =1200V, V <sub>GS</sub> =0V, T <sub>j</sub> =25°C	-	0.7	100	uA
Gate to Body Leakage Current 栅极-源极漏泄电流	$I_{GSS}$	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	-	-	200	nA
Static Drain-source On		$V_{GS}$ =20V, $I_{D}$ =10A, $T_{J}$ =25 °C	-	160	192	
Resistance <sup>(Fig.4)</sup> 漏极-源极通态电阻	R <sub>DS(on)</sub>	$V_{GS}=20V, I_{D}=10A, T_{J}=150$ °C	-	285	-	mΩ
Gate Threshold Voltage(Fig.6)	V <sub>GS(th)</sub>	$V_{DS}$ = $V_{GS}$ , $I_{DS}$ = $2.5$ mA $T_{J}$ = $25$ °C	2.0	-	4.0	V
栅极-源极阈值电压		$V_{DS}$ = $V_{GS}$ , $I_{DS}$ = $2.5$ mA $T_J$ = $150$ °C	-	1.8	-	
Gate Resistance 栅极电阻	$R_{G}$	f=1MHz, V <sub>AC</sub> =25mV	-	5.8	-	Ω
Dynamic Characteristic 动态特性						
Input Capacitance <sup>(Fig.8)</sup> 输入电容	C <sub>iss</sub>		-	950	-	
Output Capacitance 输出电容	Coss	$V_{DD} = 1000V$ , f=1MHz, $V_{GS} = 0V$ , $V_{AC} = 25mV$	-	35	-	pF
Reverse Transfer Capacitance 反向传输电容	$C_{rss}$	v AC 25HIV	-	8.5	-	
Total Gate Charge <sup>(Fig.9)</sup> 栅极总电荷	Qg(tot)		-	42	-	
Gate-source Charge 栅-源电荷	$Q_{\mathrm{gs}}$	$V_{DD} = 800 V$ , $I_D = 10 A$ , $V_{GS} = -5/20 V$	-	9	-	nC
Gate-Drain Charge 栅-漏电荷	$Q_{ m gd}$		-	17	-	



# Switching Characteristic at $T_j$ =25°C (Inductive Load)

Tj=25℃时开关特性(电感负载)

Parameter	Symbol	Conditions 条件	Value 值			IIn:4
Parameter 参数	Symbol 符号		Min. 最小 值	Typ. 典型 值	Max. 最大 值	Unit 单位
MOSFET Characteristic MOSFET 特性						
Turn-on delay time 开通延迟时间	$t_{d(on)}$	V <sub>DS</sub> =800V,	-	12	-	
Rise time 上升时间	$t_{\rm r}$	$V_{GS}$ =-5/20V, $I_{D}$ =10A,	-	20	-	
Turn-off delay time 关断延迟时间	$t_{d(off)}$	$R_{G(ext)}=2.5\Omega,$ $R_{L}=80\Omega,$	-	15	-	ns
Fall time 下降时间	$t_{\mathrm{f}}$	Tj=25°C;	-	10	-	
Turn-on Switching Energy 开通损耗	Eon	$V_{DS}$ =800V, $V_{GS}$ =-5/20V, $I_{D}$ =10A,	-	95	-	
Turn-off Switching Energy 关断损耗	Eoff	$R_{G(ext)}$ =2.5 $\Omega$ , L=256 $\mu$ H, $T_{J}$ =25 $^{\circ}$ C	-	48	-	μJ
SOURCE-DRAIN DIODE CHARAC 源极-漏极二极管特性	CTERISTIC	CS				
Source to Drain Diode Forward Voltage <sup>(Fig.7)</sup>	X.	$V_{GS}$ =-5V, $I_{SD}$ =5A, $T_{j}$ =25°C;	-	3.5	-	<b>V</b>
源极-漏极正向电压	$ m V_{SD}$	$V_{GS}$ =-5V, $I_{SD}$ =5A, $T_{j}$ =150°C;	-	3.3	-	V
Continuous Diode Forward Current 正向电流	$I_{S}$	T <sub>C</sub> =25°C;	-	-	17	A
Reverse recovery time 反向恢复时间	$t_{ m rr}$	$T_j=25$ °C, $V_{GS}=-5$ V	-	27	-	ns
Recovered charge 恢复电荷	Qrr	$V_R = 800V$	-	123	-	μС
Peak reverse recovery current 反向峰值电流	$I_{rrm}$	I <sub>SD</sub> =10A, diF/dt=1000A/μs		8.5		A

#### Notes

a: Repetitive Rating: Pulse width limited by maximum junction temperature

b: Pulse Test : Pulse width  $\leq\!\!380\mu s$ 

c: Essentially independent of operating temperature

注:

a: 重复范围: 脉冲宽度受限于最大结温

b: 脉冲测试: 脉冲宽度≤380µs

c: 本质上与工作温度无关



# Electrical characteristics diagram 特性曲线

Figure 1. Output Characteristics  $T_J = -55^{\circ}C$ 

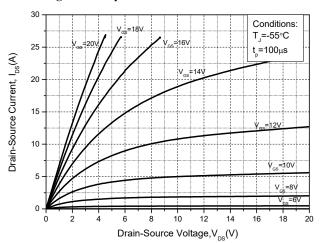


Figure 2. Output Characteristics  $T_J = 25^{\circ}C$ 

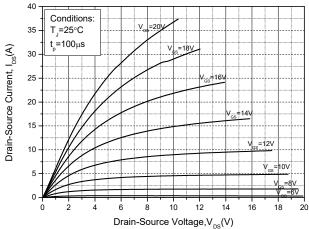


Figure 3. Output Characteristics T<sub>J</sub> =175°C

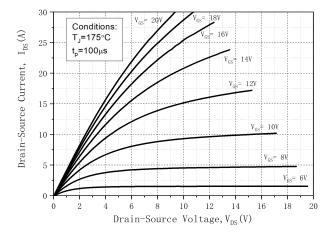


Figure 4. On-Resistance For Various Gate Voltage

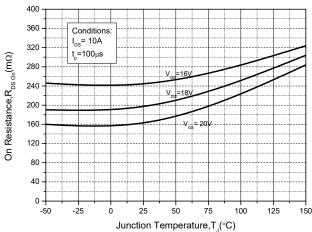


Figure 5. Transfer Characteristic for Various Junction Temperatures

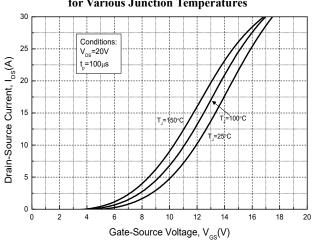


Figure 6. Threshold Voltage vs. Temperature

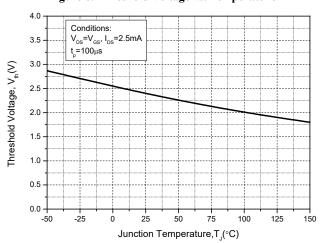




Figure 7. Body Diode Characteristics

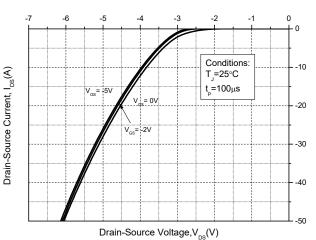


Figure 8. Capacitances vs. Drain-Source Voltage

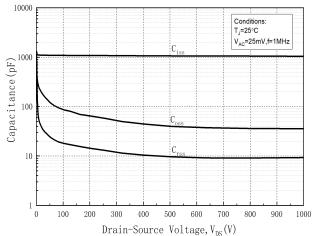


Figure 9. Gate Charge Characteristics

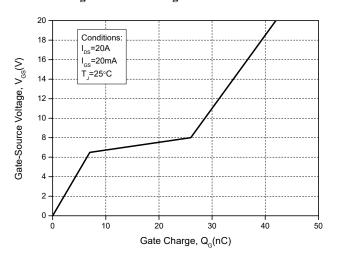


Figure 10. Power Dissipation Derating

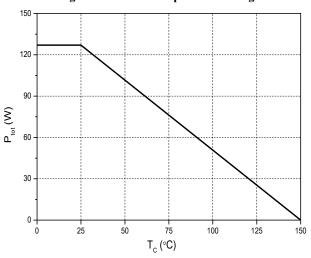
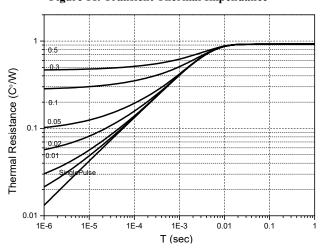
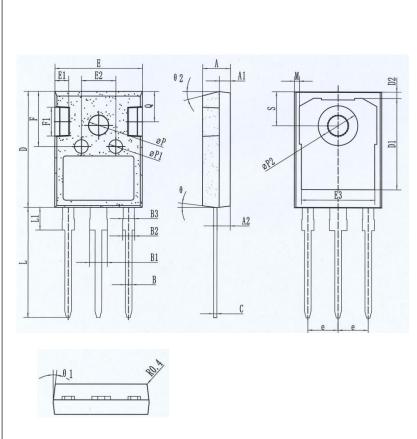


Figure 11. Transient Thermal Impendance





# TO-247 Packing Outline Dimensions: TO-247 封装外形尺寸



Dim	Mechanical Dimensions /mm				
	MIN	NOM	MAX		
A	4.90	5.00	5.10		
A1	1.90	2.00	2.10		
A2	2.30	2.40	2.50		
В	1.10	1.20	1.30		
B1	3.05	3.15	3.25		
B2	2.00	2.10	2.20		
C	0.55	0.60	0.65		
D	20.90	21.00	21.10		
D1	16.35	16.55	16.75		
E	15.70	15.80	15.90		
E1	2.40	2.50	2.60		
F	9.80	10.00	10.20		
F1	5.10	5.20	5.30		
e		5.44 BSC			
L	19.72	19.92	20.12		
L1	3.90	4.10	4.30		
ФР	3.50	3.60	3.70		
<b>Φ</b> P1	2.40	2.50	2.60		
ФР2	7.10	7.20	7.30		
S	6.05	6.15	6.25		
M	0.45	-	0.95		
Q	5.40	5.50	5.60		

Packing 包装

i doning				
Package 包装	Pcs/tube 片/管	Tube/ inner box 管/内盒	Inner box/ carton 内盒/外箱	Pcs/carton 片/外箱
Tube 管	30	12	6	2160



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